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## Expression of concern: Structural, morphological, electrical, and dielectric properties of $\text{Na}_2\text{Cu}_5(\text{Si}_2\text{O}_7)_2$ for ASSIBs

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 Expression of concern for 'Structural, morphological, electrical, and dielectric properties of  $\text{Na}_2\text{Cu}_5(\text{Si}_2\text{O}_7)_2$  for ASSIBs' by Mohamed Ben Bechir *et al.*, *RSC Adv.*, 2024, 14, 9228–9242, <https://doi.org/10.1039/D4RA01454E>.

*RSC Advances* is publishing this expression of concern in order to alert readers about concerns that have been raised regarding the BVS analysis and the NPD measurement. An expression of concern will continue to be associated with the article until a conclusive outcome is reached.

Laura Fisher  
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 Executive Editor, *RSC Advances*

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